

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/714,830	LAYFIELD, DEREK J.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0103610	06-2004	Axsom, Erich Jason	052/481.1
	B	US-6,901,713	06-2005	Axsom, Erich Jason	52/481.1
	C	US-2004/0068948	04-2004	Wrass, Lawrence J.	052/309.7
	D	US-2004/0000113	01-2004	Alderman, Robert J.	52/407.5
	E	US-2003/0061777	04-2003	Alderman, Robert J.	52/407.3
	F	US-5,907,932	06-1999	LeConte et al.	52/144
	G	US-4,603,527	08-1986	Vercelletto, Antoine	52/410
	H	US-6,401,417	06-2002	Leblang, Dennis	52/481.1
	I	US-2004/0221518	11-2004	Westra, Steven P.	052/079.1
	J	US-5,092,100	03-1992	Lambert et al.	52/774
	K	US-4,435,936	03-1984	Rutkowski, Edward J.	52/481.1
	L	US-4,047,355	09-1977	Knorr, William L.	52/733.2
	M	US-6,745,531	06-2004	Egan, William F.	52/302.1

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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	U	
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	W	
	X	

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,209,282	04-2001	Lafrance, Claudex	52/729.1
B	US-6,185,895	02-2001	Rettew, Robert A.	52/528
C	US-5,502,931	04-1996	Munir, Hussain	52/144
D	US-4,658,552	04-1987	Mulford, Cass E.	52/94
E	US-4,068,434	01-1978	Day et al.	52/220.1
F	US-4,147,004	04-1979	Day et al.	52/309.9
G	US-4,161,087	07-1979	Levesque, Clarence N.	52/62
H	US-6,240,704	06-2001	Porter, William H.	52/794.1
I	US-2005/0188649	09-2005	Hagen, Hans T. JR.	052/782.1
J	US-2005/0066618	03-2005	Tucker, Mark Irvine	052/782.1
K	US-5,953,883	09-1999	Ojala, Leo V.	52/794.1
L	US-5,761,864	06-1998	Nonoshita, Tadamichi	52/302.3
M	US-3,447,275	06-1969	Vaughan et. al.	52/592.1

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A US-2005/0102969	05-2005	Burg, John Parker	052/782.1
	B US-2005/0210798	09-2005	Burg et al.	052/481.1
	C US-2005/0223671	10-2005	Korman et al.	052/607
	D US-2003/0205010	11-2003	Anglin et al.	52/238.1
	E US-6,761,004	07-2004	Anglin et al.	52/238.1
	F US-6,061,986	05-2000	Canada, Larry	52/561
	G US-6,789,977	09-2004	Layfield, Derek John	403/294
	H US-6,634,077	10-2003	Layfield, Derek John	29/525.13
	I US-2002/0162298	11-2002	Churchill et al.	52/783.12
	J US-4,879,850	11-1989	Glassco et al.	52/82
	K US-4,748,777	06-1988	Glassco et al.	52/82
	L US-5,937,588	08-1999	Gard, Marvin	52/79.1
	M US-5,398,472	03-1995	Eichelkraut, Gerald C.	52/443

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
	T				

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U		
	V		
	W		
	X		

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-3,678,640	07-1972	Tillie, Jean-Claude	52/238.1
B	US-3,423,892	01-1969	RIMINGTON JOHN KENNETH	52/241
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
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N					
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